

Notice of References Cited	Application/Control No. 10/585,333		Applicant(s)/Patent Under Reexamination KIM, HAK-YONG	
	Examiner RYAN OCHYSKI		Art Unit 1791	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,398,220 A	08-1968	PORT MORTON I et al.	264/147
*	B	US-4,434,611 A	03-1984	Hasegawa et al.	57/328
*	C	US-6,308,509 B1	10-2001	Scardino et al.	57/402
*	D	US-6,319,601 B1	11-2001	Ise et al.	428/364
*	E	US-2002/0064628 A1	05-2002	Carr et al.	428/170
*	F	US-2002/0100725 A1	08-2002	Lee et al.	210/503
*	G	US-2002/0175449 A1	11-2002	Chu et al.	264/465
*	H	US-6,520,425 B1	02-2003	Reneker, Darrell H.	239/294
*	I	US-2004/0045270 A1	03-2004	Wust et al.	057/263
*	J	US-2005/0253305 A1	11-2005	Kim et al.	264/465
*	K	US-7,354,546 B2	04-2008	Kim et al.	264/465
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	X					

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